

Source	Process	Uncertainty (%)
Electron trigger	$W_{\text{SR}} / W_{e\nu}$	1
$p_{\text{T}}^{\text{miss}}$ trigger	$W_{\text{SR}} / W_{e\nu/\mu\nu}$	0–2 (shape)
Muon reconstruction efficiency	$W_{\text{SR}} / W_{\mu\nu}$	1
Muon identification efficiency	$W_{\text{SR}} / W_{\mu\nu}$	1
Electron reconstruction efficiency	$W_{\text{SR}} / W_{e\nu}$	1
Electron identification efficiency	$W_{\text{SR}} / W_{e\nu}$	1.5
Muon veto	$W_{\text{SR}} / W_{e\nu/\mu\nu}$	<1 (shape)
Electron veto	$W_{\text{SR}} / W_{e\nu/\mu\nu}$	<1 (shape)
τ veto	$W_{\text{SR}} / W_{e\nu/\mu\nu}$	1–2 (shape)
PDF	$W_{\text{SR}} / W_{e\nu/\mu\nu}$	1–2 (shape)